So, given x_i , i=1...N, we can compute

$$s = \sqrt{\frac{1}{N-1} \sum_{i=1}^{N} (x_i - \overline{x})^2}$$
 ± $\sigma_s = \frac{s}{\sqrt{2(N-1)}}$ the sample standard deviation

What about standard deviation?

There are two limiting, but often realistic, cases in practice:

- 1) Our measurements have some fixed (a priori unknown) measurement error σ , and (s, σ_s) summarizes our knowledge of it
- 2) We measured quantity x which has its own intrinsic scatter σ (e.g. weight of a loaf of bread), and (s, σ_s) summarizes our knowledge of it (assuming here that the measurement error is negligible compared to σ).